



FPD Materials & Components and FPD Metrology

Japan Joint TC Chapter

Meeting Summary and Minutes

SEMI Standards Japan Winter Meetings

Friday, June 21, 2024

SEMI Japan/ Official Virtual TC Chapter Meeting (Hybrid)

14:00-17:15 JST

TC Chapter Announcements

Next TC Chapter Meeting:

FPD Materials & Components Japan TC Chapter and FPD Metrology Japan TC Chapter joint meeting will be held on Monday, October 21, 2024 13:00-17:00 via OVTCCM and at SEMI Japan, Tokyo, Japan.

Table 1 Meeting Attendees

Italics indicate virtual participants.

FPD Materials & Components TC Co-Chairs: Tadahiro Furukawa (Yamagata University), Ryoichi Watanabe (Japan Display), Toshimasa Eguchi (Sumitomo Bakelite)

FPD Metrology TC Co-Chairs: Ryoichi Watanabe (Japan Display), Akira Kawaguchi (Otsuka Electronics)

SEMI Staff: Akiko Yoshida (SEMI Japan)

<i>Company</i>	<i>Last</i>	<i>First</i>	<i>Company</i>	<i>Last</i>	<i>First</i>
<i>Corning International</i>	<i>Okamura</i>	<i>Haruo</i>	<i>Otsuka Electronics</i>	<i>Kawaguchi</i>	<i>Akira</i>
FUJIFILM	Ishizuka	Hiroshi	<i>Sumitomo Bakelite</i>	<i>Eguchi</i>	<i>Toshimasa</i>
<i>HOYA Corporation</i>	<i>Kondo</i>	<i>Keitaro</i>	<i>SK-Electronics</i>	<i>Miyazaki</i>	<i>Shohei</i>
Japan Display	Ryoichi	Watanabe	Yamagata University	Furukawa	Tadahiro
<i>MORESCO</i>	<i>Uehigashi</i>	<i>Atsushi</i>	SEMI Japan	Sato	Hiroshi
NIPPON STEEL Chemical & Material	Nakatsuka	Jun	SEMI Japan	Yoshida	Akiko
NIPPON STEEL Chemical & Material	Kunimatsu	Noboru			

Table 2 Leadership Changes

<i>WG/TF/SC/TC Name</i>	<i>Previous Leader</i>	<i>New Leader</i>
<i>FPD Materials & Components Japan TC Chapter</i>		
None		
<i>FPD Metrology Japan TC Chapter</i>		
None		

Table 3 TC Chapter Structure Changes

<i>Previous WG/TF/SC Name</i>	<i>New WG/TF/SC Name or Status Change</i>
<i>FPD Materials & Components Japan TC Chapter</i>	
None	

Table 3 TC Chapter Structure Changes

<i>Previous WG/TF/SC Name</i>	<i>New WG/TF/SC Name or Status Change</i>
<i>FPD Metrology Japan TC Chapter</i>	
None	

Table 4 Ballot Results

<i>Document #</i>	<i>Document Title</i>	<i>Committee Action</i>
<i>FPD Materials & Components Japan TC Chapter</i>		
7215	Reapproval of SEMI D22-0818, TEST METHOD FOR THE DETERMINATION OF COLOR, TRANSMITTANCE OF FPD COLOR FILTER ASSEMBLIES	Passed as balloted
7216	Reapproval of SEMI D29-0519, TEST METHOD FOR HEAT RESISTANCE IN FLAT PANEL DISPLAY COLOR FILTERS	Passed as balloted
7217	Reapproval of SEMI D30-0519, TEST METHOD FOR LIGHT RESISTANCE IN FLAT PANEL DISPLAY COLOR FILTERS	Passed as balloted
7218	Reapproval of SEMI D66-0519, TERMINOLOGY FOR PLASTIC SUBSTRATES OF FLEXIBLE DISPLAY	Passed as balloted
7219	Reapproval of SEMI D67-0819, TEST METHOD FOR ANTIFOULING PROPERTY AND CHEMICAL RESISTANCE OF FPD POLARIZING FILMS AND ITS MATERIALS	Passed as balloted
<i>FPD Metrology Japan TC Chapter</i>		
None		

#1 **Passed** ballots and line items will be submitted to the ISC Audit & Review Subcommittee for procedural review.

#2 **Failed** ballots and line items were returned to the originating task forces for re-work and re-balloting or abandoning.

Table 5 Activities Approved by the GCS between meetings of the TC Chapter

<i>#</i>	<i>Type</i>	<i>SC/TF/WG</i>	<i>Details</i>
<i>FPD Materials & Components TC Chapter</i>			
None			
<i>FPD Metrology TC Chapter</i>			
7156A	Ballot Authorization for Cycle 5	Picture Quality Evaluation Task Force under Korea TC Chapter	Revision to SEMI D61-0723, Test Method of Perceptual Angle for OLED Displays with title change to: Test Method of Viewing Angle for Flat Panel Displays Using Color Volume – <i>Approved by GCS on 05/13/2024</i>

Table 6 Authorized Activities

Listing of all revised or new SNARF(s) approved by the Originating TC Chapter.

<i>#</i>	<i>Type</i>	<i>SC/TF/WG</i>	<i>Details</i>
<i>FPD Materials & Components Japan TC Chapter</i>			
7256	SNARF	FPD Materials & Components Maintenance Task Force	Reapproval to SEMI D19-1019, Test Method for the Determination of Chemical Resistance of Flat Panel Display Color Filters
7257	SNARF	FPD Materials & Components Maintenance Task Force	Reapproval to SEMI D45-1019: Test Method for Resistance of Resin Black Matrix with High Resistance for FPD Color Filter

Table 6 Authorized Activities

Listing of all revised or new SNARF(s) approved by the Originating TC Chapter.

#	Type	SC/TF/WG	Details
7258	SNARF	FPD Materials & Components Maintenance Task Force	Line Item Revision to SEMI D46-1019, Terminology for FPD Polarizing Films
<i>FPD Metrology Japan TC Chapter</i>			
7259	SNARF	FPD Metrology Maintenance Task Force	Revision to SEMI D31-0318, with title change from Guide for Definition of Measurement Index (DSEmu) for Luminance Mura in FPD Image Quality Inspection to Guide for Definition of Measurement Index (DSEmu) for Luminance Mura in FPD Image Quality

#1 SNARFs and TFOFs are available for review on the SEMI Web site at:

<http://downloads.semi.org/web/wstdsbal.nsf/TFOFSNARF>

Table 7 Authorized Ballots

#	When	TF	Details
<i>FPD Materials & Components Japan TC Chapter</i>			
7256	Cycle 6-24	FPD Materials & Components Maintenance Task Force	Reapproval to SEMI D19-1019, Test Method for the Determination of Chemical Resistance of Flat Panel Display Color Filters
7257	Cycle 6-24	FPD Materials & Components Maintenance Task Force	Reapproval to SEMI D45-1019: Test Method for Resistance of Resin Black Matrix with High Resistance for FPD Color Filter
7258	Cycle 6-24	FPD Materials & Components Maintenance Task Force	Line Item Revision to SEMI D46-1019, Terminology for FPD Polarizing Films
<i>FPD Metrology Japan TC Chapter</i>			
7259	Cycle 6-24	FPD Metrology Maintenance Task Force	Revision to SEMI D31-0318, with title change from Guide for Definition of Measurement Index (DSEmu) for Luminance Mura in FPD Image Quality Inspection to Guide for Definition of Measurement Index (DSEmu) for Luminance Mura in FPD Image Quality

Table 8 SNARF(s) Granted a One-Year Extension

#	TF	Title	Expiration Date
<i>FPD Materials & Components Japan TC Chapter</i>			
None			
<i>FPD Metrology Japan TC Chapter</i>			
None			

Table 9 SNARF(s) Abolished

#	TF	Title
<i>FPD Materials & Components Japan TC Chapter</i>		
None		
<i>FPD Metrology Japan TC Chapter</i>		
None		

Table 10 Standard(s) to receive Inactive Status

Standard Designation	Title
<i>FPD Materials & Components Japan TC Chapter</i>	
None	
<i>FPD Metrology Japan TC Chapter</i>	
None	

Table 11 New Action Items

Item #	Assigned to	Details
<i>FPD Materials & Components Japan TC Chapter</i>		
FPDM&C_20240621_01	SEMI Staff	To forward the ballot adjudication result of Doc.#7215, 7216, 7217, 7218 and 7219 to ISC A&R Subcommittee for procedural review.
FPDM&C_20240621_02	FPD Materials & Components Maintenance Task Force	To submit SEMI D19 and D45 Reapproval ballots as well as D46 Line Item Revision ballot for Cycle 6.
FPDM&C_20240621_03	FPD Mask Task Force	To propose SNARF for Specification for Electrostatic Properties of FPD Photomasks and Blanks Package as well as ballot submission for Cycle 6 to GCS.
<i>FPD Metrology Japan TC Chapter</i>		
FPDMet_20240621-01	FPD Metrology Maintenance Task Force	To submit SEMI D31 Revision ballot for Cycle 6.

Table 12 Previous Meeting Action Items

Item #	Assigned to	Details
<i>FPD Materials & Components Japan TC Chapter</i>		
FPDM&C_20240216_01	SEMI Staff	To forward the ballot adjudication result of Doc.#7157 to ISC A&R Subcommittee for procedural review. →Closed
FPDM&C_20240216_02	Each Task Force Co-leaders/ SEMI Staff	To create a Connect@SEMI site for the Task Forces under FPD Materials & Components Japan TC Chapter. →Closed
FPDM&C_20240216_03	FPD Materials & Components Maintenance Task Force	To review the documents for upcoming 5-year review. →Closed
FPDM&C_20240216_04	FPD Materials & Components Maintenance Task Force/ Flexible Display Task Force	To submit Reapproval ballots for SEMI D22, D29, D30, D66, and D67 for Cycle 3. →Closed

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
FPDM&C_20240216_05	FPD Mask Task Force	To send SNARF for New Standard, Specification of the Electrostatic Properties for FPD Photomasks and Blanks Package to FPD Materials & Components Global Technical Committee members for two weeks review. →Open
<i>FPD Metrology Japan TC Chapter</i>		
FPDMet_20240216-1	FPD Metrology Maintenance Task Force	To submit SNARF for Revision to SEMI D31, Guide for Definition of Measurement Index (DSemu) for Luminance Mura in FPD Image Quality Inspection. →Closed
FPDMet_20240216-2	FPD Metrology Maintenance Task Force Co-Leaders/ SEMI Staff	To create a Connect@SEMI site for the FPD Metrology Maintenance Task Force. →Closed

1 Welcome, Reminders, and Introductions

Tadahiro Furukawa called the meeting to order at 14:00. The meeting reminders on antitrust issues, intellectual property issues and holding meetings with international attendance were reviewed. Attendees introduced themselves.

Attachment: 01_Required Meeting Elements March 2024_J

2 Review of Previous Meeting Minutes

The FPD Materials & Components Japan TC Chapter and the FPD Metrology Japan TC Chapter reviewed the minutes of the previous meeting.

Motion: Approve the minutes for the previous FPD M&C and FPD Metrology Japan TC Chapter joint meeting with two corrections.

By / 2nd: By: Ryoichi Watanabe/ Japan Display Inc.
Second: Hiroshi Ishizuka/ FUJIFILM

Discussion: None.

Vote: 6-Y 0-N. Motion Passed.

Attachment: 02_FPD M&C+FPD Met_JA_Mins_20240216_R1

3 Liaison Reports

3.1 Japan Regional Standards Committee (JRSC)

Akiko Yoshida (SEMI Japan) reported for the JRSC. At the previous meeting held on April 9, the JRSC recommended that GoToMeeting, which has been used for many years as an official web conferencing system for audio and visual content for the Japan TC Chapter meetings, be replaced by Microsoft Teams due to recent connection problems.

Tadahiro Furukawa (Yamagata University) also reported that the Planning Meeting will be held on Friday, August 31 inviting all the TF leaders as well as TC co-chairs to discuss emerging standardization issues related to Digital Twin. Program members other than leadership level will also be invited if they are recommended by the TC co-chairs.

3.2 Global Coordinating Subcommittee (GCS)

3.2.1 FPD Materials and Components Japan TC Chapter

None.

3.2.2 FPD Metrology Japan TC Chapter

Akiko Yoshida (SEMI Japan) reported for the GCS of the global FPD Metrology TC that Doc.#7156A, Revision to SEMI D61-0723, Test Method of Perceptual Angle for OLED Displays with title change to: Test Method of Viewing Angle for Flat Panel Displays Using Color Volume was authorized to be submitted for Cycle 5 by the GCS on May 13, 2024.

3.3 FPD Metrology Korea TC Chapter

Akiko Yoshida (SEMI Japan) reported for the FPD Metrology Korea TC Chapter. Of note:

- Jaehong Kim (LG Display) and Yongwoo Yi (Samsung Display) were newly elected as TC Chapter co-chairs.
- The Perceptual Viewing Angle Task Force and the Perceptual Image Quality Task Force were disbanded.
- The following two ballots are expected to be submitted for Cycle 6, 2024:
 - Doc.#6975D, New Standard, Test Method for Response Time Evaluation of Displays with Variable Refresh Rate
 - Doc.#7154, New Standard, Test Method for Flicker of Flat Panel Displays

Attachment: 03_Liaison report_FPDM_KR_June2024

3.4 FPD Metrology Taiwan TC Chapter

Akiko Yoshida (SEMI Japan) reported for the FPD Metrology Taiwan TC Chapter. Of note

- The following two ballots were submitted for Cycle 4, 2024, and will be adjudicated at the next TC Chapter meeting in October.
 - Doc.#7220, Reapproval of SEMI D59-0519, Terminology for 3D Display
 - Doc.#7221, Reapproval of SEMI D62-0619, Test Method for Measurement of LED Light Bar for Liquid Crystal Displays.

Attachment: 04_FPD Taiwan Liaison Report_20240223_R1

4 SEMI Staff Report

Akiko Yoshida (SEMI Japan) gave the SEMI Staff Report. Of note:

- New online voting system went live for Cycle 3, 2024. This integrates and streamlines sign-in process with various SEMI/Standards member services, and improves data management for SEMI internal database. It is also expected to bring updated user interface while maintaining functionality that's familiar to voters.
- SEMI Standards Regulations and Procedure Manual were updated in February 2024. They are available at www.semi.org/standards (under Tools for Developing Standards).
- TFs have one year from 02/20/24 to implement use of Connect@SEMI (<https://connect.semi.org>) for TF management and document development depository. Once TFs have implemented use of Connect@SEMI, they shall use it to: maintain the TF member roster up to date, share the working drafts in PDF, and distribute the Draft Document at least one week before ballot submission to SEMI.
- Meeting Required Elements have been updated to include notice on confidential information.

Attachment: 05_Staff Report March 2024 v4.2

5 Ballot Review

NOTE 1: TC Chapter adjudication of ballots is detailed in the Audits & Review (A&R) Subcommittee Forms for procedural review. The A&R forms are available as attachments to these minutes. The attachment file name for each balloted document is provided.

5.1 FPD Materials & Components Japan TC Chapter

5.1.1 *Doc.#7215, Reapproval of SEMI D22-0818, TEST METHOD FOR THE DETERMINATION OF COLOR, TRANSMITTANCE OF FPD COLOR FILTER ASSEMBLIES*

- **Passed** the TC Chapter review as balloted. Refer to attachment below for full details.

5.1.2 *Doc.#7216, Reapproval of SEMI D29-0519, TEST METHOD FOR HEAT RESISTANCE IN FLAT PANEL DISPLAY COLOR FILTERS*

- **Passed** the TC Chapter review as balloted. Refer to attachment below for full details.

5.1.3 *Doc.#7217, Reapproval of SEMI D30-0519, TEST METHOD FOR LIGHT RESISTANCE IN FLAT PANEL DISPLAY COLOR FILTERS*

- **Passed** the TC Chapter review as balloted. Refer to attachment below for full details.

5.1.4 *Doc.#7218, Reapproval of SEMI D66-0519, TERMINOLOGY FOR PLASTIC SUBSTRATES OF FLEXIBLE DISPLAY*

- **Passed** the TC Chapter review as balloted. Refer to attachment below for full details.

5.1.5 *Doc.#7219, Reapproval of SEMI D67-0819, TEST METHOD FOR ANTIFOULING PROPERTY AND CHEMICAL RESISTANCE OF FPD POLARIZING FILMS AND ITS MATERIALS*

- **Passed** the TC Chapter review as balloted. Refer to attachment below for full details.

Attachment: 06_7215_Ballot Report_Final
07_7216_Ballot Report_Final
08_7217_Ballot Report_Final
09_7218_Ballot Report_Final
10_7219_Ballot Report_Final

5.2 FPD Metrology Japan TC Chapter

None.

6 Task Force Reports

6.1 FPD Materials & Components Japan TC Chapter

6.1.1 Flexible Display Task Force

No report was provided.

6.1.2 FPD Mask Task Force

Keitaro Kondo (HOYA Corporation) reported for the FPD Mask Task Force. Of note:

- The Task Force met on March 8, 2024 and confirmed the draft document for New Standard: Specification for Electrostatic Properties of FPD Photomasks and Blanks Package. The SNARF proposal is now under two weeks GTC review. Once the process is completed, the SNARF will be submitted to GCS for approval as well as letter ballot authorization will be proposed.

- The Task Force also met on June 6, 2024 to discuss standardization issues on mask/ blanks case including recycling and more sustainable materials.
- Doc.#7157 was published as SEMI D38-0624, Guide for Quality Area of Flat Panel Display (FPD) Masks.
- Morinobu became a new Task Force member.

Attachment: 11_240318 Minutes FPD_Mask_TF-2
12_240606 Minutes FPD_Mask_TF

6.1.3 FPD Materials & Components Maintenance Task Force

Please see 7.1.2 below.

6.2 FPD Metrology Japan TC Chapter

6.2.1 FPD Metrology Maintenance Task Force

Please see 7.2.2 below.

7 Old Business

7.1 FPD Materials & Components Japan TC Chapter

7.1.1 Project Period Review

None.

7.1.2 5-year Review

Hiroshi Ishizuka (FUJIFILM) reported for the FPD Materials & Components Maintenance Task Force. The Task Force reviewed the documents listed for 5-year review and proposed SNARFs and ballot submissions.

- Reapproval to SEMI D19-1019, Test Method for the Determination of Chemical Resistance of Flat Panel Display Color Filters

Motion: Approve SNARF for Reapproval to SEMI D19-1019, Test Method for the Determination of Chemical Resistance of Flat Panel Display Color Filters

By / 2nd: Tadahiro Furukawa (Yamagata University)/ Jun Nakatsuka (NIPPON STEEL Chemical & Material)

Discussion: None.

Vote: 8-Y 0-N. Motion Passed.

Motion: Authorize the letter ballot submission for Reapproval to SEMI D19-1019, Test Method for the Determination of Chemical Resistance of Flat Panel Display Color Filters in Cycle 6.

By / 2nd: Tadahiro Furukawa (Yamagata University)/ Jun Nakatsuka (NIPPON STEEL Chemical & Material)

Discussion: None.

Vote: 7-Y 0-N. Motion Passed.

- Reapproval to SEMI D45-1019: Test Method for Resistance of Resin Black Matrix with High Resistance for FPD Color Filter

Motion: Approve SNARF for Reapproval to SEMI D45-1019: Test Method for Resistance of Resin Black Matrix with High Resistance for FPD Color Filter

By / 2nd: Tadahiro Furukawa (Yamagata University)/ Jun Nakatsuka (NIPPON STEEL Chemical & Material)

Discussion: None.

Vote: 8-Y 0-N. Motion Passed.

Motion: Authorize the letter ballot submission for Reapproval to SEMI D45-1019: Test Method for Resistance of Resin Black Matrix with High Resistance for FPD Color Filter in Cycle 6.

By / 2nd: Tadahiro Furukawa (Yamagata University)/ Jun Nakatsuka (NIPPON STEEL Chemical & Material)

Discussion: None.

Vote: 8-Y 0-N. Motion Passed.

- Line Item Revision to SEMI D46-1019, Terminology for FPD Polarizing Films

Motion: Approve SNARF for Line Item Revision to SEMI D46-1019, Terminology for FPD Polarizing Films

By / 2nd: Hiroshi Ishizuka (FUJIFILM)/ Ryoichi Watanabe (Japan Display)

Discussion: None.

Vote: 7-Y 0-N. Motion Passed.

Motion: Authorize the letter ballot submission for Line Item Revision to SEMI D46-1019, Terminology for FPD Polarizing Films in Cycle 6.

By / 2nd: Hiroshi Ishizuka (FUJIFILM)/ Ryoichi Watanabe (Japan Display)

Discussion: None.

Vote: 7-Y 0-N. Motion Passed.

Attachment: 13_SNARF_SEMI19_Chemical Resistance

14_SNARF_SEMI45_Black

15_SNARF_Line Item Revision to SEMI D46-1019_20240617hi

7.2 FPD Metrology Japan TC Chapter

7.2.1 Project Period Review

None.

7.2.2 5-Year Reviews

Ryoichi Watanabe (Japan Display) reported for the FPD Metrology Maintenance Task Force. The Task Force proposed SNARF which completed two weeks review by the Global FPD Metrology TC members. The Task Force also proposed ballot submission of SEMI D31 Revision ballot for Cycle 6.

- Revision to SEMI D31-0318, with title change from Guide for Definition of Measurement Index (DSemu) for Luminance Mura in FPD Image Quality Inspection to Guide for Definition of Measurement Index (DSemu) for Luminance Mura in FPD Image Quality

Motion: Approve the SNARF for Revision to SEMI D31-0318, with title change from Guide for Definition of Measurement Index (DSemu) for Luminance Mura in FPD Image Quality Inspection to Guide for Definition of Measurement Index (DSemu) for Luminance Mura in FPD Image Quality

By / 2nd: Akira Kawaguchi (Otsuka Electronics)/ Tadahiro Furukawa (Yamagata University)

Discussion: None.

Vote: 7-Y 0-N. Motion Passed.



Motion: Authorize the Letter Ballot for Revision to SEMI D31-0318, with title change from Guide for Definition of Measurement Index (DSemu) for Luminance Mura in FPD Image Quality Inspection to Guide for Definition of Measurement Index (DSemu) for Luminance Mura in FPD Image Quality for Cycle 6.

By / 2nd: Akira Kawaguchi (Otsuka Electronics)/ Tadahiro Furukawa (Yamagata University)

Discussion: None.

Vote: 8-Y 0-N. Motion Passed.

Attachment: 16_SNARF_D31 Revision_R1

8 New Business

8.1 FPD Materials & Components Japan TC Chapter

None.

8.2 FPD Metrology Japan TC Chapter

None.

9 Action Item Review

9.1 Open Action Items

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
<i>FPD Materials & Components Japan TC Chapter</i>		
FPDM&C_20240216_01	SEMI Staff	To forward the ballot adjudication result of Doc.#7157 to ISC A&R Subcommittee for procedural review. →Closed
FPDM&C_20240216_02	Each Task Force Co-leaders/ SEMI Staff	To create a Connect@SEMI site for the Task Forces under FPD Materials & Components Japan TC Chapter. →Closed
FPDM&C_20240216_03	FPD Materials & Components Maintenance Task Force	To review the documents for upcoming 5-year review. →Closed
FPDM&C_20240216_04	FPD Materials & Components Maintenance Task Force/ Flexible Display Task Force	To submit Reapproval ballots for SEMI D22, D29, D30, D66, and D67 for Cycle 3. →Closed
FPDM&C_20240216_05	FPD Mask Task Force	To send SNARF for New Standard, Specification of the Electrostatic Properties for FPD Photomasks and Blanks Package to FPD Materials & Components Global Technical Committee members for two weeks review. →Open
<i>FPD Metrology Japan TC Chapter</i>		
FPDMet_20240216-1	FPD Metrology Maintenance Task Force	To submit SNARF for Revision to SEMI D31, Guide for Definition of Measurement Index (DSemu) for Luminance Mura in FPD Image Quality Inspection. →Closed
FPDMet_20240216-2	FPD Metrology Maintenance Task Force Co-Leaders/ SEMI Staff	To create a Connect@SEMI site for the FPD Metrology Maintenance Task Force. →Closed

9.2 New Action Items

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
<i>FPD Materials & Components Japan TC Chapter</i>		
FPDM&C_20240621_01	SEMI Staff	To forward the ballot adjudication result of Doc.#7215, 7216, 7217, 7218 and 7219 to ISC A&R Subcommittee for procedural review.
FPDM&C_20240621_02	FPD Materials & Components Maintenance Task Force	To submit D19 and D45 Reapproval ballots, and D46 Line Item Revision ballot for Cycle 6.
FPDM&C_20240621_03	FPD Mask Task Force	To propose SNARF for Specification for Electrostatic Properties of FPD Photomasks and Blanks Package as well as ballot submission for Cycle 6 to GCS.
<i>FPD Metrology Japan TC Chapter</i>		
FPDMet_20240621-01	FPD Metrology Maintenance Task Force	To submit SEMI D31 Revision ballot for Cycle 6.

10 Next Meeting and Adjournment

FPD Materials & Components Japan TC Chapter and FPD Metrology Japan TC Chapter joint meeting will be held on Monday, October 21, 2024 13:00-17:00 via OVTCCM and at SEMI Japan, Tokyo, Japan.

See <http://www.semi.org/standards-events> for the current list of events.

Adjournment: [17:20].

Respectfully submitted by:

Akiko Yoshida

Standards & EHS

SEMI Japan

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Minutes tentatively approved by:

<i>FPD Materials & Components Japan TC Chapter</i>	
Tadahiro Furukawa (Yamagata University), Co-chair	July 9, 2024
Ryoichi Watanabe (Japan Display), Co-chair	July 9, 2024
Toshimasa Eguchi (Sumitomo Bakelite), Co-chair	July 10, 2024
<i>FPD Metrology Japan TC Chapter</i>	
Ryoichi Watanabe (Japan Display), Co-chair	July 9, 2024
Akira Kawaguchi (Otsuka Electronics), Co-chair	July 9, 2024



Table 13 Index of Available Attachments#1

<i>Title</i>	<i>Title</i>
01_Required Meeting Elements March 2024_J	09_7218_Ballot Report_Final
02_FPD M&C+FPD Met_JA_Mins_20240216_R1	10_7219_Ballot Report_Final
03_Liaison report_FPDM_KR_June2024	11_240318 Minutes FPD_Mask_TF-2
04_FPD Taiwan Liaison Report_20240223_R1	12_240606 Minutes FPD_Mask_TF
05_Staff Report March 2024 v4.2	13_SNARF_SEMI19_Chemical Resistance
06_7215_Ballot Report_Final	14_SNARF_SEMI45_Black
07_7216_Ballot Report_Final	15_SNARF_Line Item Revision to SEMI D46-1019_20240617hi
08_7217_Ballot Report_Final	16_SNARF_D31 Revision_R1

#1 Due to file size and delivery issues, attachments must be downloaded separately. A .zip file containing all attachments for these minutes is available at www.semi.org. For additional information or to obtain individual attachments, please contact Akiko Yoshida at the contact information above.